

General Description

The AO6422 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for general purpose application.

Features

$$V_{DS} = 20V$$

$$I_D = 5A \quad (V_{GS} = 4.5V)$$

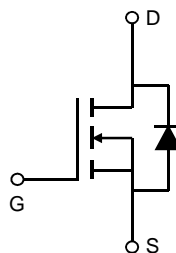
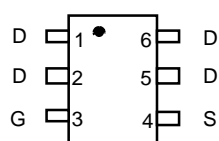
$$R_{DS(ON)} < 44m\Omega \quad (V_{GS} = 4.5V)$$

$$R_{DS(ON)} < 55m\Omega \quad (V_{GS} = 2.5V)$$

$$R_{DS(ON)} < 72m\Omega \quad (V_{GS} = 1.8V)$$



Top View



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | 10 Sec | Steady State | Units | |
|--|----------------|------------------|--------------|------------|---|
| Drain-Source Voltage | V_{DS} | 20 | | V | |
| Gate-Source Voltage | V_{GS} | ± 8 | | V | |
| Continuous Drain Current ^A | I_D | $T_A=25^\circ C$ | 5 | 3.9 | A |
| | | $T_A=70^\circ C$ | 4.2 | 3 | |
| Pulsed Drain Current ^B | I_{DM} | 30 | | | |
| Power Dissipation ^A | P_D | $T_A=25^\circ C$ | 2.0 | 1.1 | W |
| | | $T_A=70^\circ C$ | 1.3 | 0.7 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | | $^\circ C$ | |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|------|------|--------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 47.5 | 62.5 | $^\circ C/W$ |
| $t \leq 10s$ | | | | |
| Maximum Junction-to-Ambient ^A | $R_{\theta JL}$ | 54 | 68 | $^\circ C/W$ |
| Steady State | | | | |
| Maximum Junction-to-Lead ^C | | | | |

Electrical Characteristics (T_J=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|--|--------------------------------------|----------|----------|-------|
| STATIC PARAMETERS | | | | | | |
| B _V DSS | Drain-Source Breakdown Voltage | I _D = 250μA, V _{GS} = 0V | 20 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 20V, V _{GS} = 0V T _J = 55°C | | | 1 5 | μA |
| I _{GSS} | Gate-Body leakage current | V _{DS} = 0V, V _{GS} = ±8V | | | ±100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} = V _{GS} , I _D = 250μA | 0.4 | 0.65 | 1 | V |
| I _{D(ON)} | On state drain current | V _{GS} = 4.5V, V _{DS} = 5V | 30 | | | A |
| R _{DS(ON)} | Static Drain-Source On-Resistance | V _{GS} = 4.5V, I _D = 5.0A T _J = 125°C | | 35 48 | 44 60 | mΩ |
| | | V _{GS} = 2.5V, I _D = 4.5A | | 43 | 55 | |
| | | V _{GS} = 1.8V, I _D = 3.5A | | 55 | 72 | mΩ |
| g _{FS} | Forward Transconductance | V _{DS} = 5V, I _D = 5.0A | | 14 | | S |
| V _{SD} | Diode Forward Voltage | I _S = 1A, V _{GS} = 0V | | 0.8 | 1 | V |
| I _S | Maximum Body-Diode Continuous Current | | | | 2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} = 0V, V _{DS} = 10V, f = 1MHz | | 450 | 560 | pF |
| C _{oss} | Output Capacitance | | | 74 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 52 | | pF |
| R _g | Gate resistance | V _{GS} = 0V, V _{DS} = 0V, f = 1MHz | | 4.9 | 7.5 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q _g (4.5V) | Total Gate Charge | V _{GS} = 4.5V, V _{DS} = 10V, I _D = 5A | | 6.2 | 8.2 | nC |
| Q _{gs} | Gate Source Charge | | | 0.4 | | nC |
| Q _{gd} | Gate Drain Charge | | | 1.3 | | nC |
| t _{D(on)} | Turn-On DelayTime | V _{GS} = 4.5V, V _{DS} = 10V, R _L = 2Ω, R _{GEN} = 3Ω | | 4.5 | | ns |
| t _r | Turn-On Rise Time | | | 6 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | 33 | | ns |
| t _f | Turn-Off Fall Time | | | 7.1 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | | I _F = 5A, di/dt = 100A/μs | | 13 | 17 |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F = 5A, di/dt = 100A/μs | | 3.3 | | nC |

A: The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A = 25° C. in any given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using t ≤ 300μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A = 25° C. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

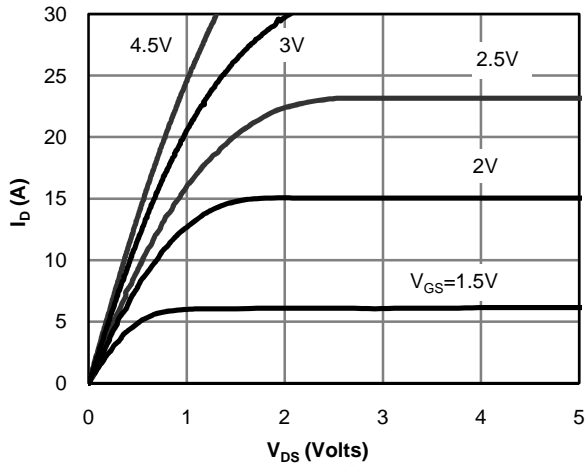


Figure 1: On-Region Characteristics

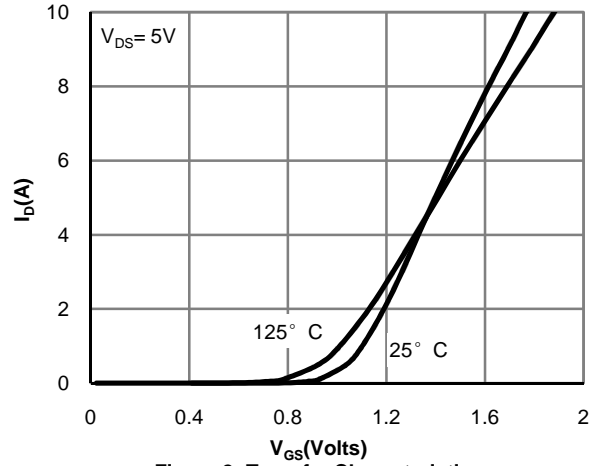


Figure 2: Transfer Characteristics

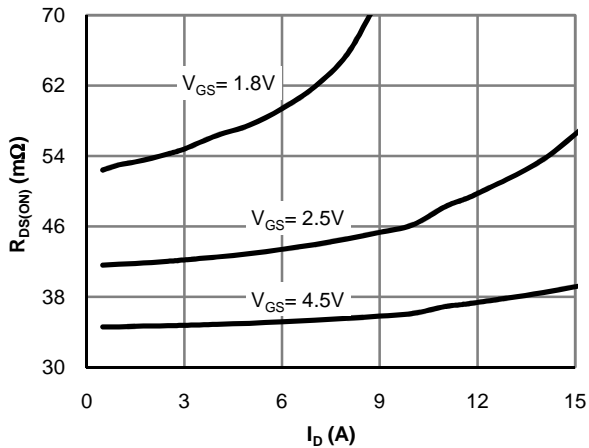


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

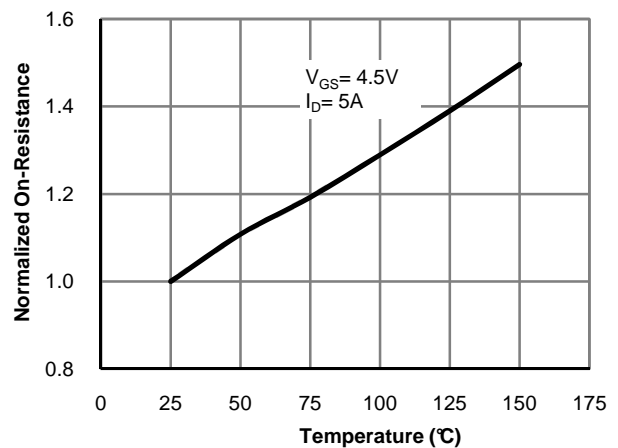


Figure 4: On-Resistance vs. Junction Temperature

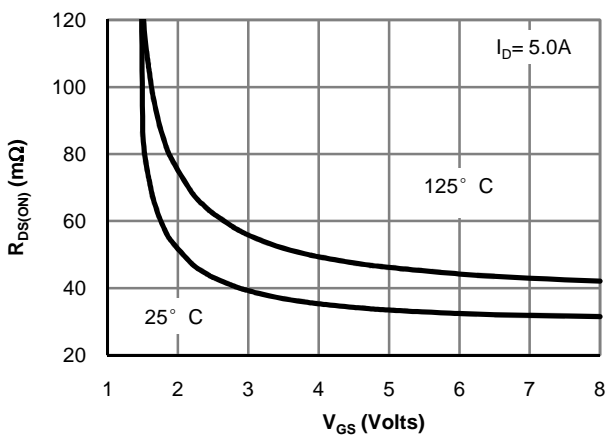


Figure 5: On-Resistance vs. Gate-Source Voltage

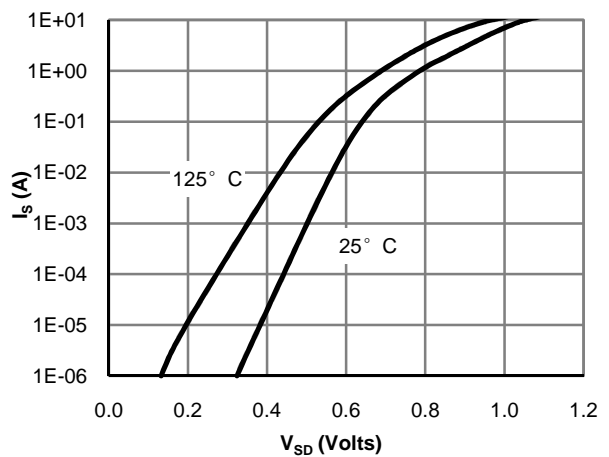


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

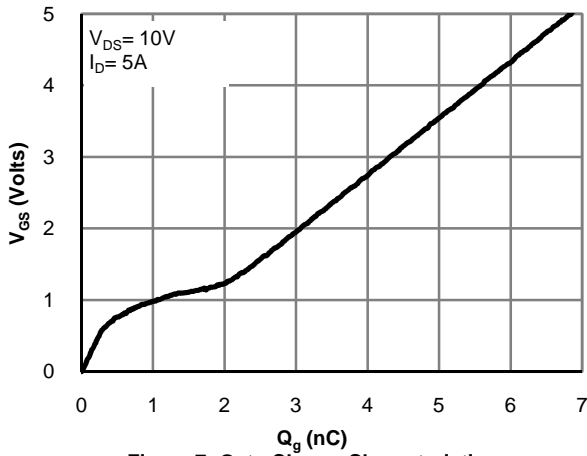


Figure 7: Gate-Charge Characteristics

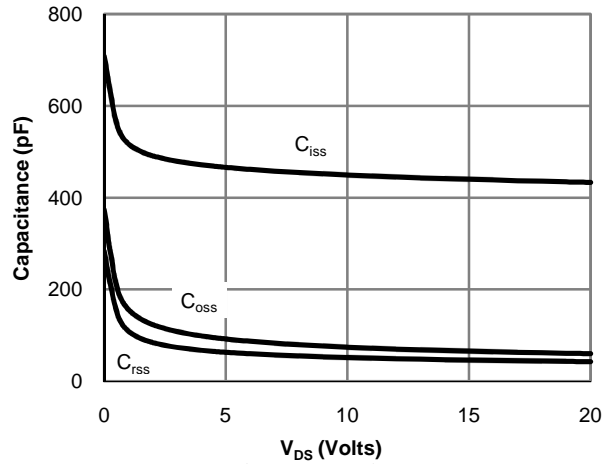


Figure 8: Capacitance Characteristics

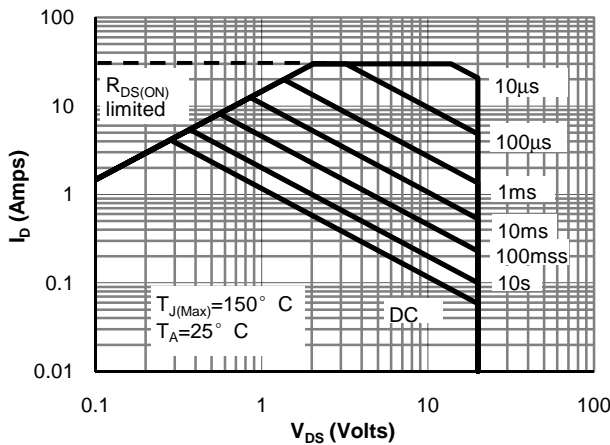


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

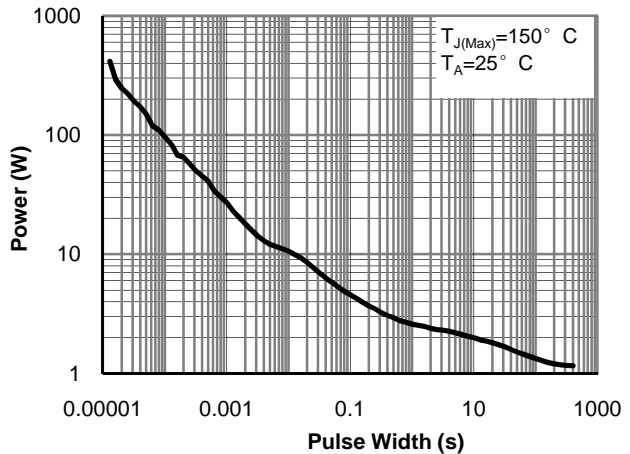


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

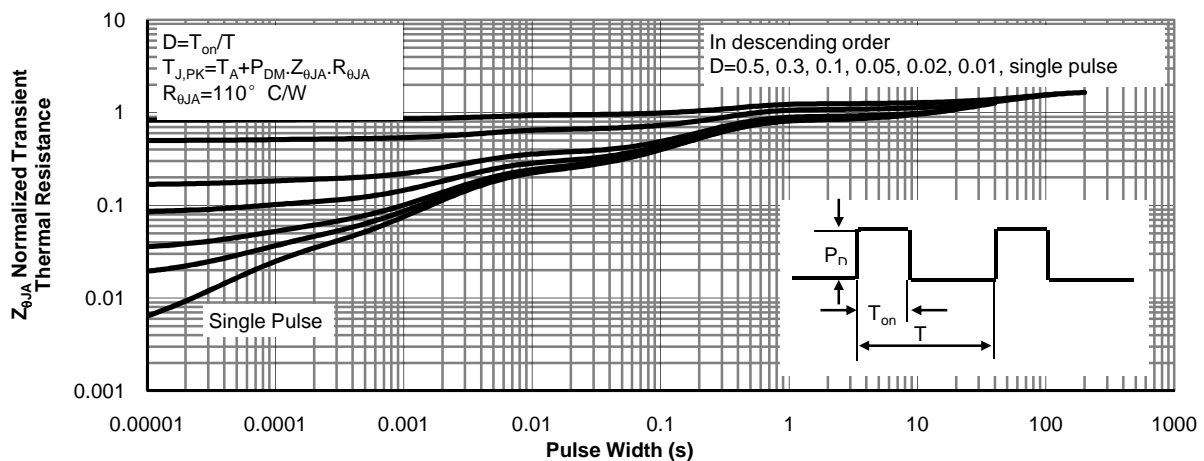


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)